

# Search notes

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	26	257/106.ccor.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 10:48
L3	40	257/199.ccor.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 10:53
L4	21	257/322.ccor.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 10:56
L5	15	257/481.ccor.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 10:56
L6	41	257/603.ccor.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 10:56
L7	10	(zener) near3 (chain or string) and (soi or silicon-on-insulator or tfsoi or thin adj film or tft or buried adj oxide)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 11:04
L9	443	(overvoltage or over-voltage or electrostatic near discharge or electro-static near discharge or eov or esd) and (zener or diode) near4 (chain or string)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 11:05
L10	174	(overvoltage or over-voltage or electrostatic near discharge or electro-static near discharge or eov or esd) and (zener) near4 (plural or plurality or chain or string)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 11:06
S1	98	(overvoltage or over-voltage or electrostatic near discharge or electro-static near discharge or eov or esd) and (zener) near5 (forward or direct or directly) near2 (biased or biasing or polarized or polarizing or polarization or bias)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 08:52
S3	146	(overvoltage or over-voltage or electrostatic near discharge or electro-static near discharge or eov or esd) and (zener or diode) near2 (forward or direct or directly) near (biased or biasing or polarized or polarizing or polarization or bias) and (soi or silicon-on-insulator or tfsoi or thin adj film or buried adj oxide)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 09:09
S4	114	(overvoltage or over-voltage or electrostatic near discharge or electro-static near discharge or eov or esd) and (zener or diode) near2 (forward or direct or directly) near (biased or biasing or polarized or polarizing or polarization or bias) near5 (plural or plurality or series or chain or string)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 11:04
S5	6	(zener) near6 (forward or direct or directly) near (biased or biasing or polarized or polarizing or polarization or bias) near5 (plural or plurality or series or chain or string) and (soi or silicon-on-insulator or tfsoi or thin adj film or tft or buried adj oxide)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 11:03

S6	137	257/173.ccor.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 09:42
S7	14	257/175.ccor.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 09:43
S8	581	257/355.ccor.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 10:45

# Interference Search

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L11	17	((zener) and (soi or tft or tfsoi or thin adj film or buried near oxide or buried near insulator or silicon-on-insulator or semiconductor-on-insulator or (silicon or semiconductor or semiconducting) near2 layer near3 (oxide or insulator or insulating or dielectric)) and (electrostatic or electro-static or esd or eov or overvoltage or discharge)).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 11:23
L14	18	((zener) near3 (series or chain or string) near10 (forward or direct or directly) near2 (biased or polarized or biasing or bias or polarization or polarizing or polarity)).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 11:27
L15	50	((zener) near4 (forward or direct or directly) near2 (biased or polarized or biasing or bias or polarization or polarizing or polarity)).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 11:29
L16	262	((diode) near4 (forward or direct or directly) near2 (biased or polarized or biasing or bias or polarization or polarizing or polarity) and (electrostatic or electro-static or esd or eov or overvoltage or over-voltage or discharge)).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/14 11:30